Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a TO263 (D2PAK) surface mountable plastic package intended for use in circuits where high static and dynamic dV/dt and high dl/dt can occur. This "series C" triac will commutate the full RMS current at the maximum rated junction temperature without the aid of a snubber.

2. Features and benefits

- 3Q technology for improved noise immunity
- · High commutation capability with maximum false trigger immunity
- · High voltage capability
- · Less sensitive gate for high noise immunity
- · Planar passivated for voltage ruggedness and reliability
- · Surface mountable package
- · Triggering in three quadrants only
- · Very high immunity to false turn-on by dV/dt

3. Applications

- · Electronic thermostats (heating and cooling)
- · High power motor controls e.g. washing machines and vacuum cleaners
- Rectifier-fed DC inductive loads e.g. DC motors and solenoids

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|---------------------|--|--|-----|-----|-----|------|
| V_{DRM} | repetitive peak off-state voltage | | - | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 100 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | - | - | 12 | А |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig 4; Fig 5 | - | - | 100 | А |
| | | full sine wave; $T_{j(init)}$ = 25 °C; t_p = 16.7 ms | - | - | 110 | Α |
| T _j | junction temperature | | - | - | 125 | °C |
| Static ch | aracteristics | | | | ' | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;}$ $T_j = 25 \text{ °C; } Fig. 7$ | 2 | - | 35 | mA |

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|--------------------------------------|---|-----|-----|-----|------|
| | | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$ | 2 | - | 35 | mA |
| | | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 7$ | 2 | - | 35 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 35 | mA |
| V_T | on-state voltage | I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.3 | 1.6 | V |
| Dynamic | characteristics | | | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 500 | - | - | V/µs |
| dI _{com} /dt | rate of change of commutating curren | $V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ (snubberless condition)}; gate open circuit$ | 20 | - | - | A/ms |

5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|------------------------|----------------|
| 1 | T1 | main terminal 1 | | N 1 |
| 2 | T2 | main terminal 2 | | T2—T1 |
| 3 | G | gate | | sym051 |
| mb | T2 | mounting base; main terminal 2 | 1 3 TO-263 (D2PAK) E N | |

6. Ordering information

Table 3. Ordering information

| Type number | Package Name | Orderable part number | Packing method | Small packing quantity | Package version | Package issue date |
|--------------|-----------------|-----------------------|----------------|------------------------|-----------------|--------------------|
| BTA312B-800C | TO263 | BTA312B-800C,118 | Reel | 800 | TO263E (E) | 26-May-2017 |
| | | | | | TO263N (N) | 26-Sep-2016 |

7. Marking

Table 4. Marking codes

| Type number | Marking codes | | |
|--------------|-------------------------------|-------------------------------|--|
| | Assembly factory: E | Assembly factory: N | |
| BTA312B-800C | BTA312B 800C PJExxxx xx | BTA312B 800C PJNxxxx xx | |

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--|--|-----|-----|------------------|
| V_{DRM} | repetitive peak off-state voltage | | - | 800 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; T _{mb} ≤ 100 °C; Fig. 1; Fig. 2; Fig. 3 | - | 12 | А |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig 4; Fig 5 | - | 100 | А |
| | | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$ | - | 110 | Α |
| I ² t | I ² t for fusing | t _P = 10 ms; SIN | - | 50 | A ² s |
| dl _⊤ /dt | rate of rise of on-state current | I _G = 70 mA | - | 100 | A/µs |
| I _{GM} | peak gate current | | - | 2 | Α |
| P_GM | peak gate power | | - | 5 | W |
| $P_{G(AV)}$ | average gate power | over any 20 ms period | - | 0.5 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| T _j | junction temperature | | - | 125 | °C |

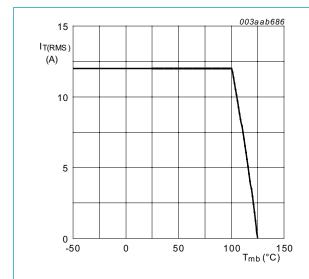
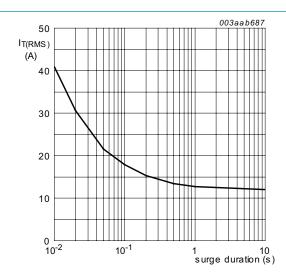
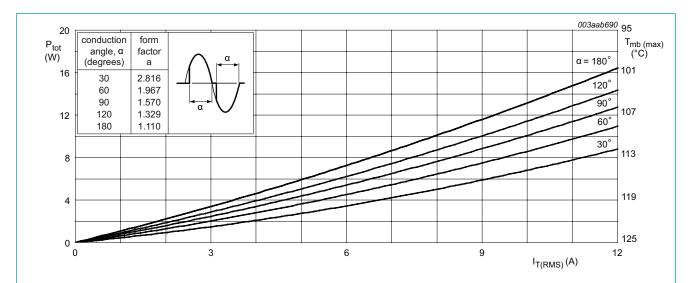


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



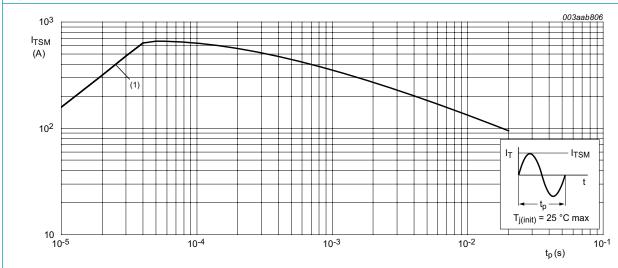
f = 50 Hz; T_{mb} = 100 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



 α = conduction angle

a = form factor = $I_{T(RMS)}/I_{T(AV)}$

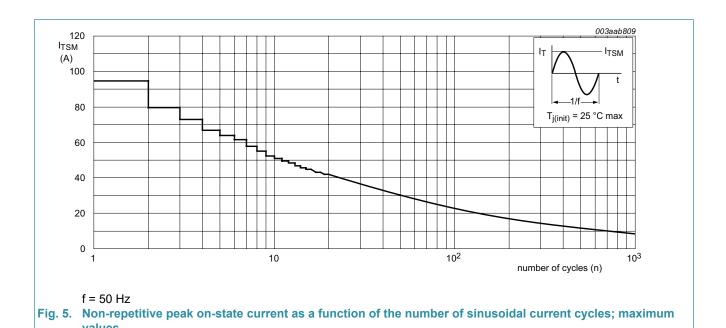
Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



t_p ≤ 20 ms

(1) dl_T/dt limit

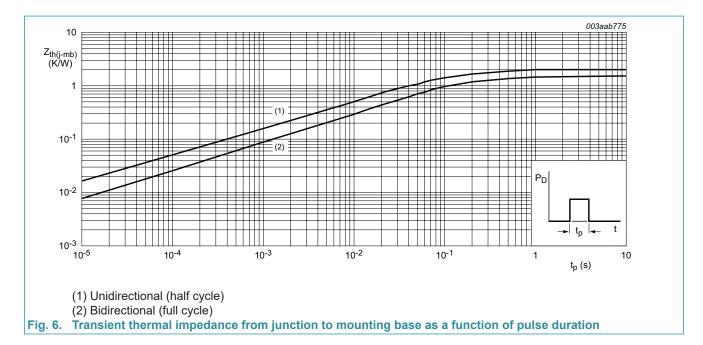
Fig. 4. Non-repetitive peak on-state current as a function of pulse duration; maximum values



9. Thermal characteristics

Table 6. Thermal characteristics

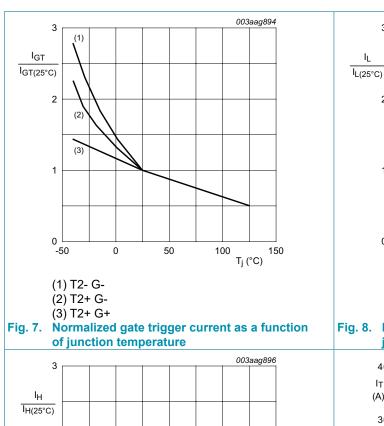
| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---|-------------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance | full cycle; Fig 6 | - | - | 1.5 | K/W |
| | from junction to mounting base | half cycle; Fig 6 | - | - | 2 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient | in free air | - | 55 | - | K/W |



10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|---|------|-----|-----|------|
| Static ch | aracteristics | | | | | |
| I _{GT} g | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | 2 | - | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$ | 2 | - | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{ G-};$ $T_j = 25 \text{ °C}; Fig. 7$ | 2 | - | 35 | mA |
| IL | latching current | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 50 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | - | 60 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 8}}$ | - | - | 50 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | - | 35 | mA |
| V_T | on-state voltage | I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.3 | 1.6 | V |
| V_{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11 | - | 0.8 | 1 | V |
| | | $V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 125 \text{ °C};$ Fig. 11 | 0.25 | 0.4 | - | V |
| I _D | off-state current | V _D = 800 V; T _j = 125 °C | - | 0.1 | 0.5 | mA |
| Dynamic | characteristics | | ' | | ' | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 536 V; T_{j} = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 500 | - | - | V/µs |
| dI _{com} /dt | rate of change of commutating current | $V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ (snubberless condition)}; gate open circuit$ | 20 | - | - | A/ms |



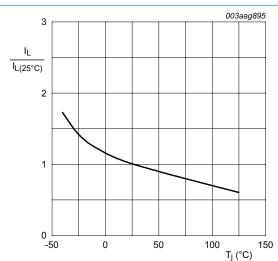
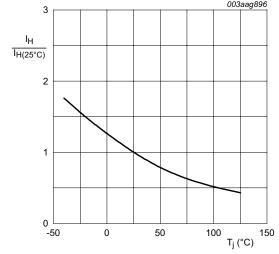
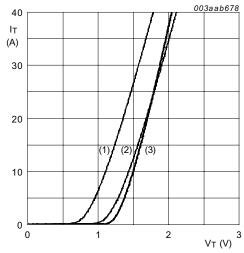


Fig. 8. Normalized latching current as a function of junction temperature

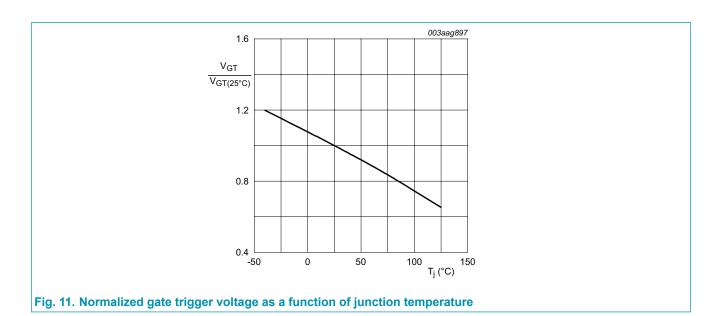




 V_o = 1.164 V; R_s = 0.027 Ω (1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values (3) T_i = 25 °C; maximum values

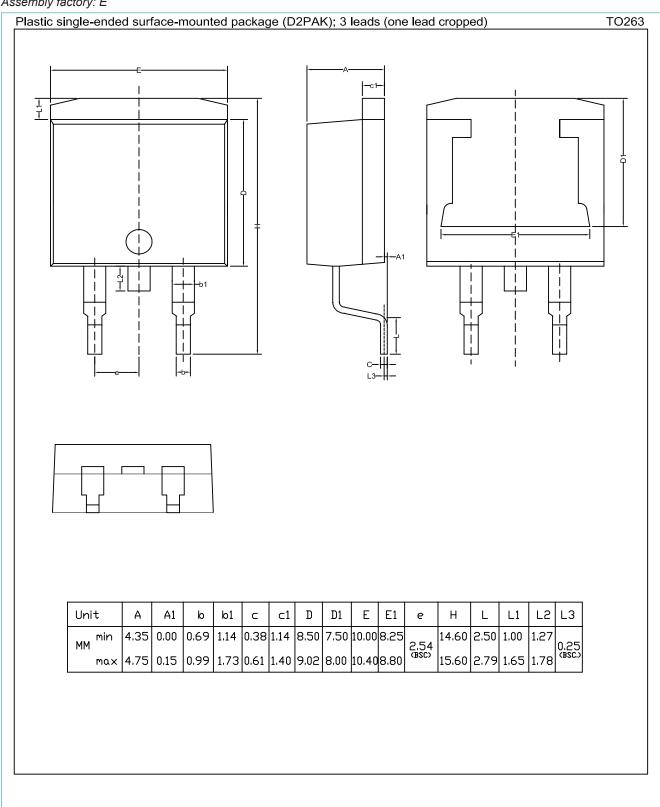
Fig. 9. Normalized holding current as a function of junction temperature

Fig. 10. On-state current as a function of on-state voltage

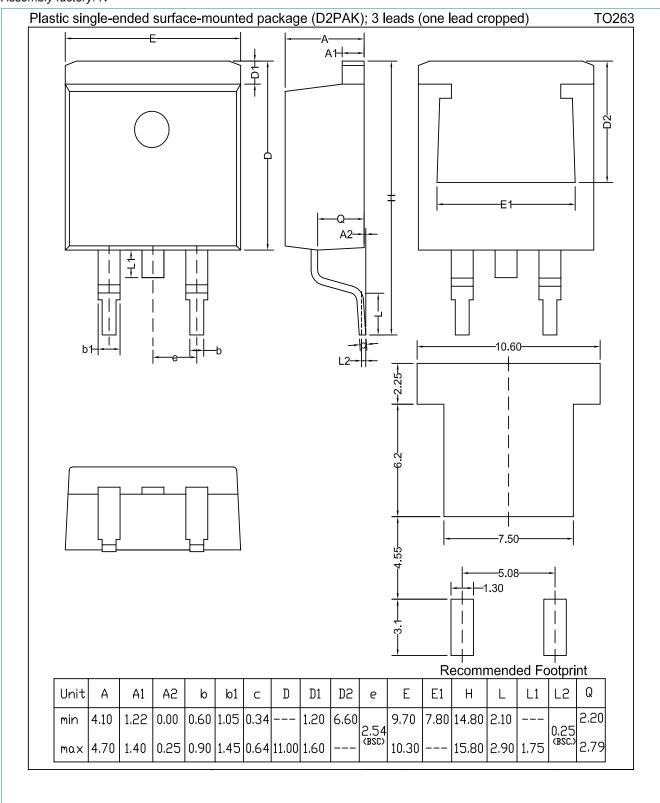


11. Package outline

Assembly factory: E



Assembly factory: N



12. Legal information

Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
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For more information, please visit: http://www.ween-semi.com
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